

Fig. 1

Title: System And Method For Chip Testing

Inventor: Joseph Weiyeh Ku

HP PDNO.: 10008039-1

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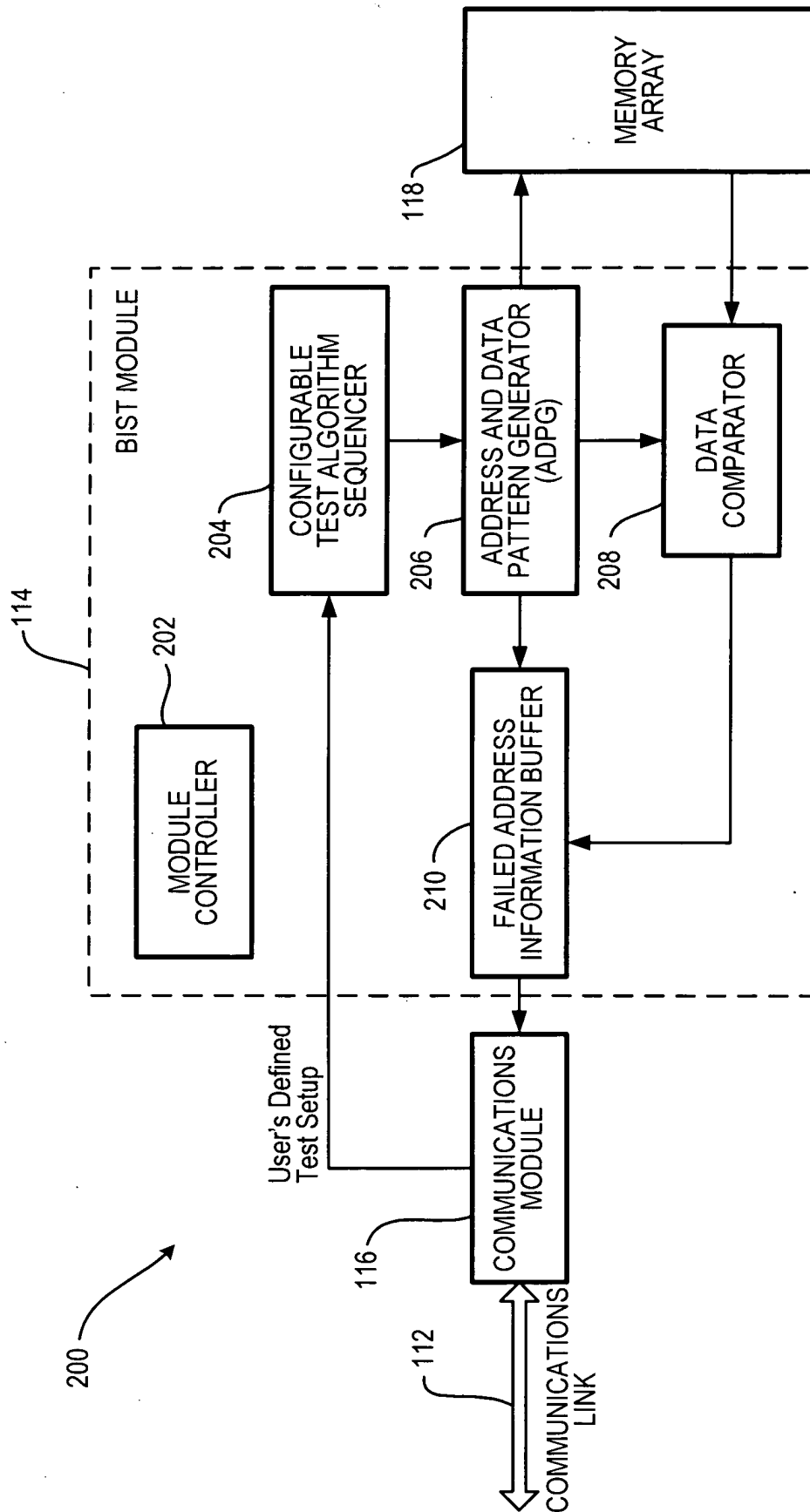
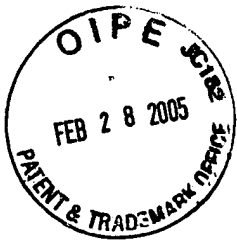
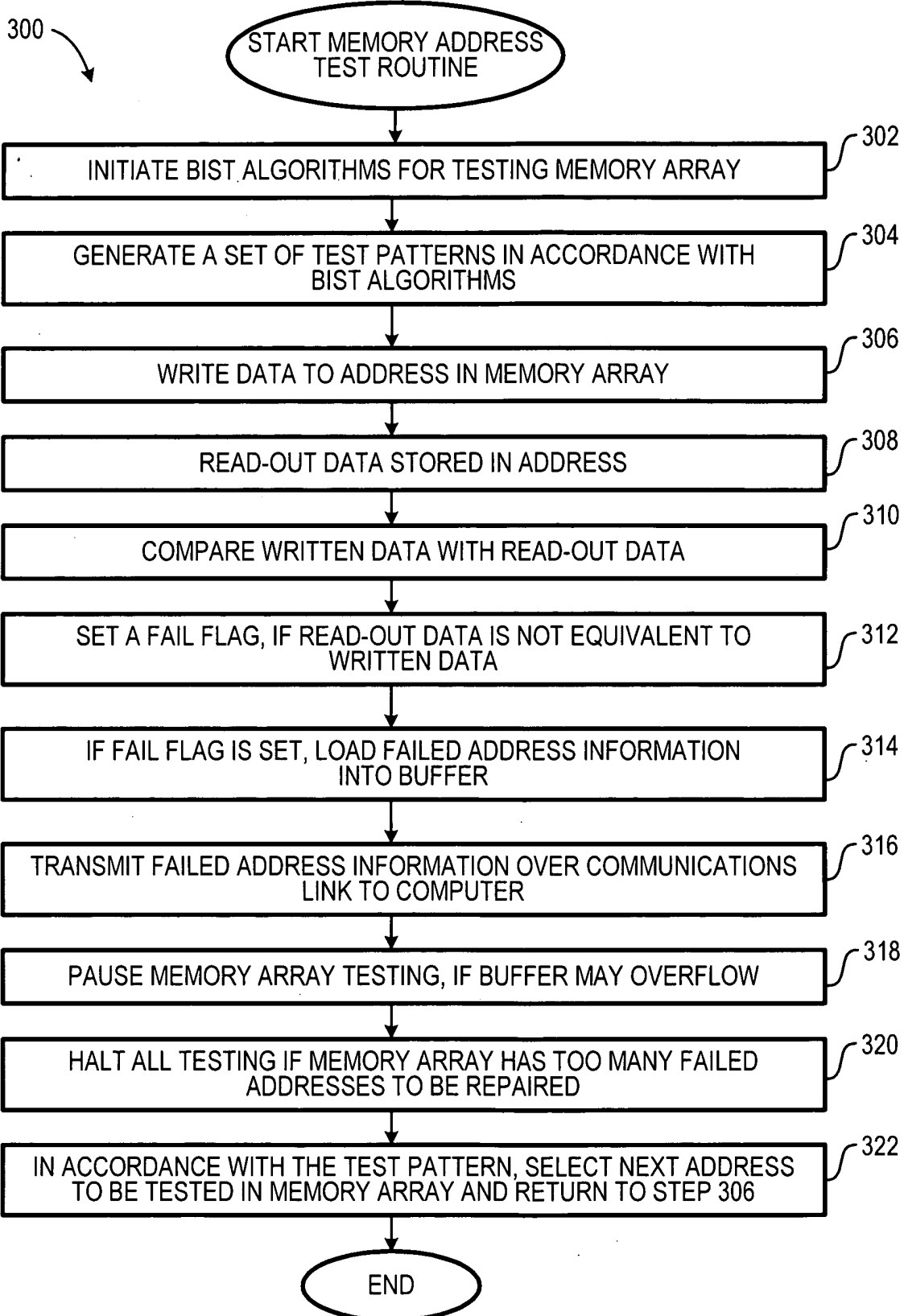
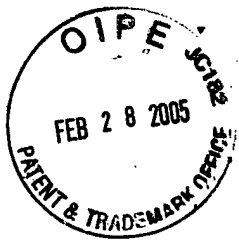


Fig. 2



**Fig. 3**

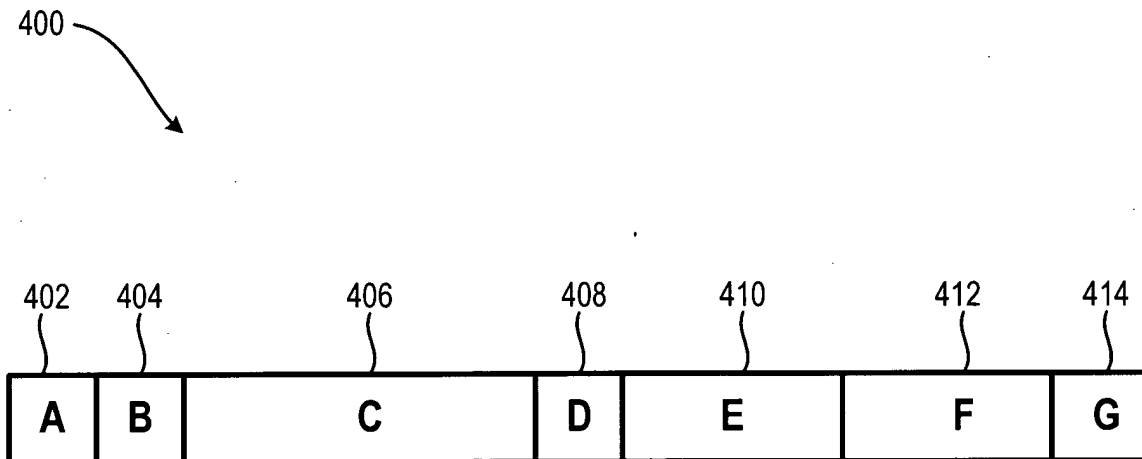


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FIELD:

DATA CONTENTS:

A

HEADER

B

FAILED ADDRESS LENGTH

C

FAILED ADDRESS

D

FAILED DATA LENGTH

E

DATA WRITTEN

F

DATA READ-OUT

G

FAILED BIT LOCATIONS

Fig. 4